

## Debug Policy

DPK has not been provided and will not be programmed.  
SmartDebug user debug access and active probes are enabled.  
SmartDebug Live Probe debug access is enabled.  
SmartDebug sNVM debug is enabled.  
JTAG or SPI Slave UJTAG is enabled.  
JTAG (1149.1) boundary scan is enabled.  
JTAG or SPI Slave reading of temperature and voltage sensor is enabled.

## Microsemi Factory Access

Allow Microsemi factory test mode access. This is required to perform Failure Analysis on the device.

## Security key mode

- Bitstream encryption with default key       Custom security options

User keys

Update policy

Debug policy

Microsemi  
factory  
accessJTAG/SPI Slave  
commands  
policy

Debugging is enabled by default at this stage for design and debug.  
Use FlashLock/UPK1 or DPK to temporarily enable access to disabled debug features during one debugging session.

DPK (Debug Pass Key) (64 HEX chars):

0x



SmartDebug access control

- Disable user debug access and active probes  
 Disable Live Probe  
 Disable sNVM
- Disable UJTAG command through JTAG interface  
 Disable JTAG (1149.1) boundary scan  
 Disable reading temperature and voltage sensor (JTAG/SPI Slave)

Reset to default

Help

Save Summary to File...

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Finish

Cancel